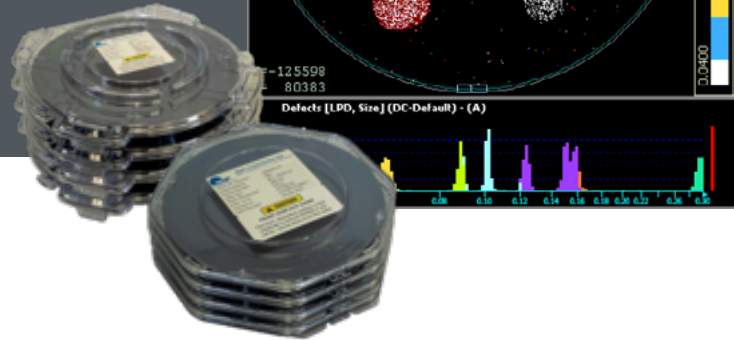




SP3, SP5, and SP7 Calibration Standards



Traceable, Consistent, Convenient

SP3, 5, & 7 Calibration Standards are precision-engineered tools for the calibration, verification and re-qualification of the most common wafer surface inspection systems (like Surfscan® from KLA) used in semiconductor manufacturing. These standards play a crucial role in ensuring the accuracy and reliability of inspection equipment, which is essential to maintain high yields and quality in mature nodes of semiconductor fabrication for years to come.

Based on a combination of industry-leading equipment knowledge and particle deposition expertise, MSP provides a comprehensive line of NIST-traceable Calibration Standards, including documentation of manufacturing processes and controls, inspection reports using a Surfscan® tool, and other certification guarantees. This ensures that customers receive best-in-class standards with the narrowest particle distributions, highest particle size accuracy for their critical surface inspection applications.

MSP's *Cal-Dep™* portfolio ensures that this industry workhorse inspection equipment is calibrated to factory standards so fabs can continue to operate at peak performance.

Applications

- Inspection tool qualification
- Inspection tool calibration
- Process tool monitoring
- Bare silicon wafer IQC/OQC
- Advanced Process Control (APC)

Features

- NIST traceability
- Multiple wafer sizes
- Highest accuracy calibration standards
- Competitive pricing
- Designed for fab environment

Benefits

- Fast delivery
- Easy ordering
- Conforms to OEM calibration requirements
- Particle sizes matched to original calibration curves

Specifications

SP3, SP5, and SP7 Calibration Standards

Our Offerings - Request a quote to see all variants!

SP3 — Full-Wafer, Single Size Only

Broadest range of simple single-size wafers.

- 14 nominal/NIST sizes, 32nm–1500nm
- Count: 20,000 ± 6,000

SP5 — Full-Wafer + Multi-Spot Options

Adds multi-spot flexibility.

- Full deposit (3 nominal/NIST sizes: 60/90/300nm) — count 20,000 ± 6,000
- Multi-spot (dual/6-spot/8-spot, covering 22nm–1500nm) — count 2,000 ± 600

SP7 — Full-Wafer + Multi-Spot + Finest Sizes

Adds the finest particle sizes (down to 18nm) and a unique combo full+center-spot design.

- Full deposit (60nm) — count 20,000 ± 6,000
- Full + center-spot combo (60nm) — dual count spec
- Multi-spot (dual/6-spot/8-spot, covering 18nm–1500nm) — count 2,000 ± 600

Specifications

- Low-haze 300mm bare silicon wafer
- SiO₂ spheres
- Cert of conformance
- Deposition summaries
- Particle traceability
- Particle counts +/- 25%
- Spot wafers: 20 mm spot diameter

Surfscan is a registered trademark of KLA Corporation

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MSP - Visit our website www.tsi.com/msp for more information.

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